

February 1999

FDS6975 Dual P-Channel, Logic Level, PowerTrench[™] MOSFET

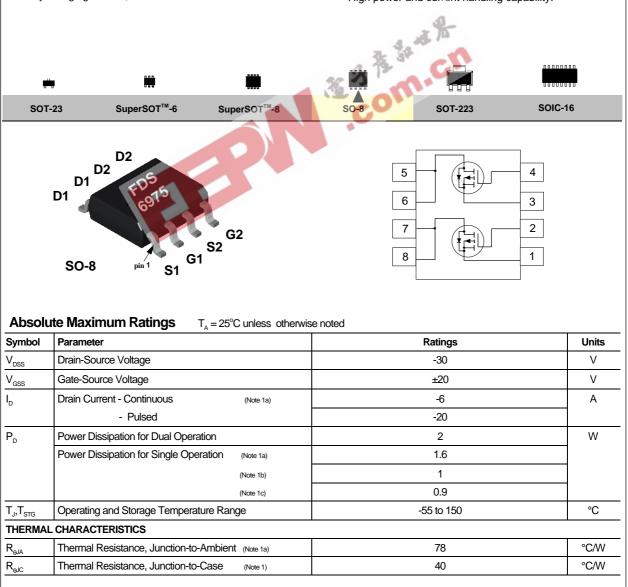
General Description

These P-Channel Logic Level MOSFETs are produced using Fairchild Semiconductor's advanced PowerTrench process that has been especially tailored to minimize the on-state resistance and yet maintain low gate charge for superior switching performance.

These devices are well suited for notebook computer applications: load switching and power management, battery charging circuits, and DC/DC conversion.

Features

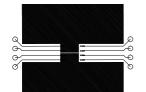
- -6 A, -30 V. $R_{DS(ON)} = 0.032 \Omega @ V_{GS} = -10 V,$ $R_{DS(ON)} = 0.045 \Omega @ V_{GS} = -4.5 V.$
- Low gate charge (14.5nC typical).
- High performance trench technology for extremely low R_{DS(ON)}.
- High power and current handling capability.



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Symbol	Parameter	Conditions	Min	Тур	Max	Units
OFF CHAR	ACTERISTICS					•
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 V, I_{D} = -250 \mu A$	-30			V
$\Delta BV_{DSS} / \Delta T_{J}$	Breakdown Voltage Temp. Coefficient	$I_{\rm D}$ = -250 µA, Referenced to 25 °C		-21		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -24 V, V_{GS} = 0 V$			-1	μA
		$T_{J} = 55^{\circ}C$			-10	μA
GSSF	Gate - Body Leakage, Forward	$V_{GS} = 20 \text{ V}, \text{ V}_{DS} = 0 \text{ V}$			100	nA
GSSR	Gate - Body Leakage, Reverse	$V_{gs} = -20 V, V_{ps} = 0 V$			-100	nA
ON CHARAC	CTERISTICS (Note 2)			1	1	
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	-1	-1.7	-3	V
$\Delta V_{GS(th)} / \Delta T_J$	Gate Threshold Voltage Temp. Coefficient	$I_{\rm D}$ = 250 µA, Referenced to 25 °C		4		mV/ºC
R _{DS(ON)}	Static Drain-Source On-Resistance	$V_{GS} = -10 \text{ V}, \text{ I}_{D} = -6 \text{ A}$		0.025	0.032	Ω
		T _J =125°C	;	0.033	0.051	
		$V_{GS} = -4.5 \text{ V}, \text{ I}_{D} = -5 \text{ A}$		0.034	0.045	
D(ON)	On-State Drain Current	$V_{GS} = -10 \text{ V}, V_{DS} = -5 \text{ V}$	-20			Α
9 _{FS}	Forward Transconductance	$V_{DS} = -10 \text{ V}, \text{ I}_{D} = -6 \text{ A}$	20	16		S
DYNAMIC C	HARACTERISTICS	7. 18	-			
C _{iss}	Input Capacitance	$V_{DS} = -15 V$, $V_{GS} = 0 V$, f = 1.0 MHz		1540		pF
C _{oss}	Output Capacitance	f = 1.0 MHz		400		pF
C _{rss}	Reverse Transfer Capacitance			170		pF
SWITCHING	CHARACTERISTICS (Note 2)		•			
D(on)	Turn - On Delay Time	$V_{DS} = -15 V, I_{D} = -1 A$		13	24	ns
r	Turn - On Rise Time	$V_{\text{GEN}} = -10 \text{ V}, \text{R}_{\text{GEN}} = 6 \Omega$		22	35	ns
D(off)	Turn - Off Delay Time			47	75	ns
f	Turn - Off Fall Time			18	30	ns
2 [°]	Total Gate Charge	$V_{DS} = -10 \text{ V}, \text{ I}_{D} = -6 \text{ A},$		14.5	20	nC
2 _{qs}	Gate-Source Charge	V _{GS} = -5 V		4		nC
J ^{ad}	Gate-Drain Charge			5		nC
DRAIN-SOUI	RCE DIODE CHARACTERISTICS AND MAXIN	IUM RATINGS				1
S	Maximum Continuous Drain-Source Diode F	rce Diode Forward Current			-1.3	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 V, I_{S} = -1.3 A$ (Note 2)		-0.73	-1.2	V

R_{gut} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{gut} is guaranteed by design while R_{gut} is determined by the user's board design.





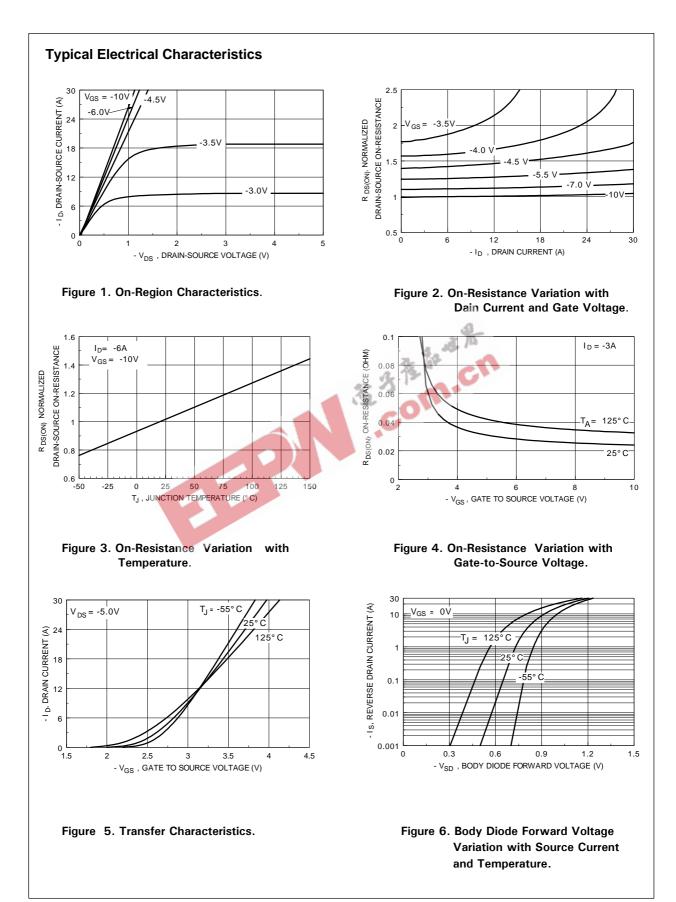


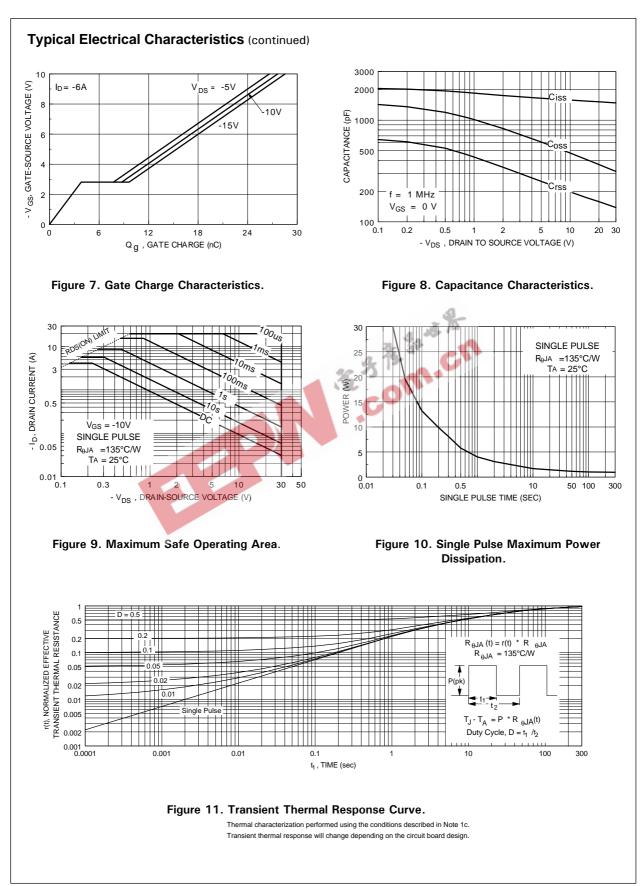


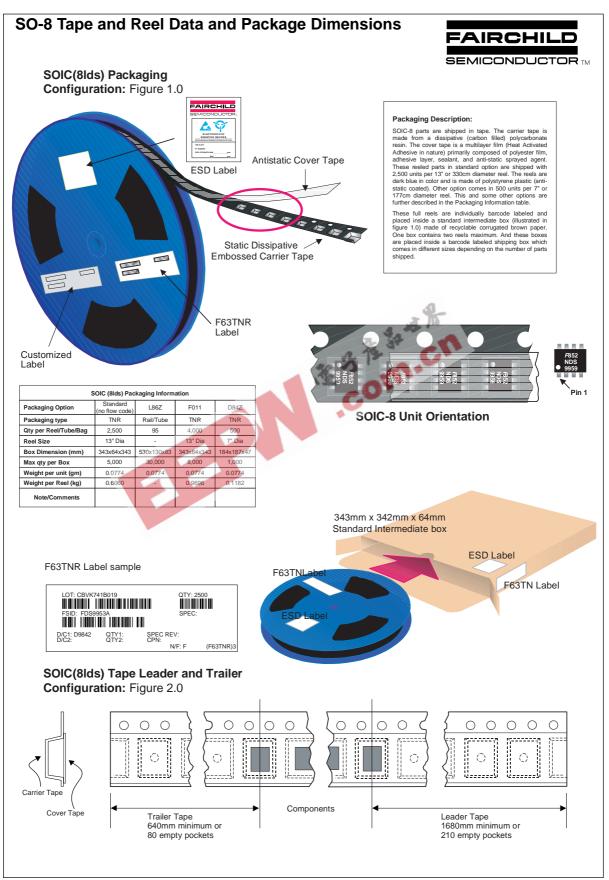
b. 125°C/W on a 0.02 in² pad of 2oz copper.

Scale 1 : 1 on letter size paper

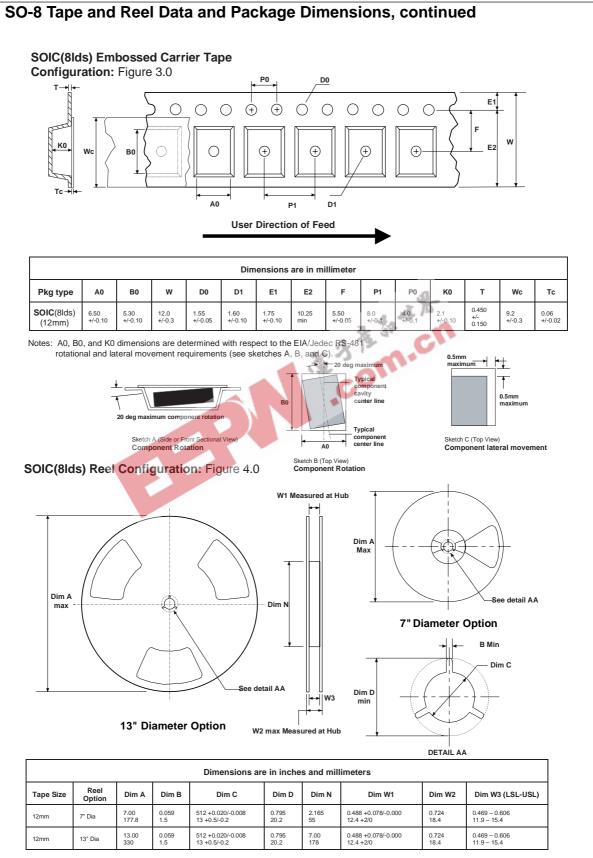
2. Pulse Test: Pulse Width \leq 300 μ s, Duty Cycle \leq 2.0%.

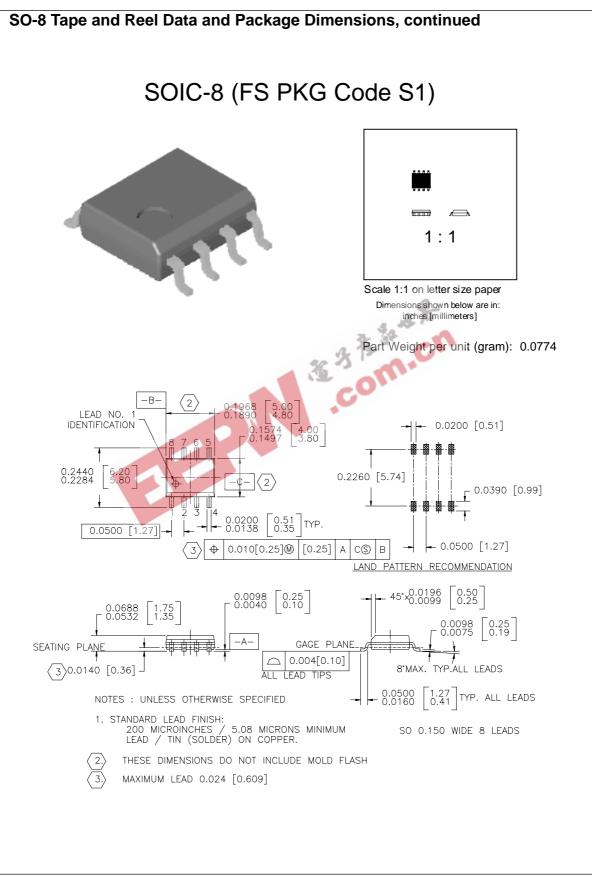






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